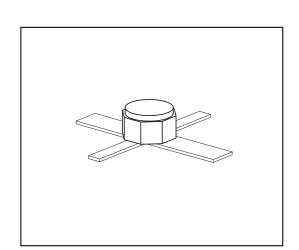


HiRel NPN Silicon RF Transistor

HiRel Discrete and Microwave Semiconductor

- For Medium Power Amplifiers
- Compression Point $P_{-1dB} = 19 \text{ dbm } 1.8 \text{ GHz}$ Max. available gain $G_{ma} = 16 \text{ dB at } 1.8 \text{ GHz}$
- Hermetically sealed microwave package
- Transitor frequency $f_T = 20 \text{ GHz}$
- SIEGET ® 25 GHz f_T Line
 Infineon Technologies Grounded Emitter Transistor 25 GHz f_T- Line



• **esa** Space Qualified

ESA/SCC Detail Spec. No.: 5611/008

Type Variant No. 03

ESD: Electrostatic discharge sensitive device, observe handling precaution!

Туре	Marking	Pin Configuration						Package
BFY450 (ql)	-	1=C	2=E	3=B	4=E	-	-	MICRO-X

(ql) Testing level: P: Professional testing

H: High Rel quality S: Space quality ES: ESA qualified

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{\sf CEO}$	4.5	V
Collector-base voltage	V_{CBO}	15	
Emitter-base voltage	V_{EBO}	1.5	
Collector current	I _C	100	mA
Base current	l _B	10	
Total power dissipation	P _{tot}	450	mW
$T_{\rm S} \le 110 {}^{\circ}{\rm C}^{-1)2}$			
Junction temperature	T_{i}	175	°C
Operating temperature range	T_{op}	-65 175	°C
Storage temperature	$T_{ m stg}$	-65 175	°C

 $^{{}^{1}}T_{\rm S}$ is measured on the collector lead at the soldering point to the pcb.

²At T_S = 110°C. For T_S > 110°C derating is required.



Thermal Resistance

Parameter	Symbol	Value	Unit
Junction - soldering point ¹⁾	R_{thJS}	< 145	K/W

Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Parameter	Symbol	Values		Unit	
		min.	typ.	max.	
DC Characteristics			•	•	•
Collector-emitter cutoff current ²⁾	I _{CEX}	-	-	200	μA
$V_{CE} = 4.5 \text{ V}, I_{B} = 1 \mu\text{A}$					
Collector -base cutoff current	I _{CBO}	-	-	100	nA
$V_{CB} = 5 \text{ V}, I_{E} = 0$					
Emitter-base cutoff current	/ _{EBO}	-	-	50	μA
$V_{\rm EB} = 1.5 \rm V, \ I_{\rm C} = 0$					
DC current gain	h _{FE}	50	90	150	-
$I_{\rm C} = 20 \text{ mA}, \ V_{\rm CE} = 1 \text{ V}$					

 $^{^{1}\}textit{T}_{S}$ is measured on the collector lead at the soldering point to the pcb.

 $^{^2}$ This test assures $V_{(BR)CE0} > 4.5 \text{ V}$



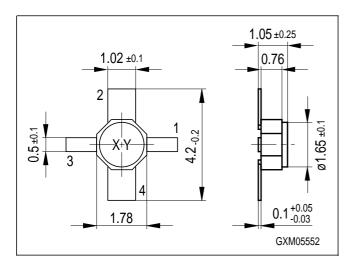
Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Symbol	Values			Unit
	min.	typ.	max.	
ıg)				
f _T				GHz
	18	22	-	
	-	17	-	
C_{cb}	-	0.42	0.9	pF
C _{ce}	-	1.27	2.6	
C _{eb}	-	2	3	
F	-	1.25	2	dB
G _{ma} 1)	-	16	-	
S _{21e} ²	8	12	-	dB
P _{-1dB}	-	19	-	dBm
	$f_{ m T}$ $f_{ m T}$ $C_{ m cb}$ $C_{ m ce}$ $C_{ m eb}$ F $G_{ m ma}^{1)}$	min. f_T 18 - - C_{cb} - C_{ce} - C_{eb} - $C_{ma}^{(1)}$ - $ S_{21e} ^2$ 8	min. typ. fT 18 22 - 17 C_{cb} - 0.42 C_{ce} - 1.27 C_{eb} - 2 F - 1.25 $G_{ma}^{1)}$ - 16 $ S_{21e} ^2$ 8 12	min. typ. max. fT 18 22 - - 17 - C_{cb} - 0.42 0.9 C_{ce} - 1.27 2.6 C_{eb} - 2 3 F - 1.25 2 $G_{ma}^{1)}$ - 16 - $ S_{21e} ^2$ 8 12 -

 $^{^{1}}G_{\text{ma}} = |S_{21e} / S_{12e}| (k-(k^{2}-1)^{1/2})$



Micro-X Package





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